Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/335,581	BANNAN ET AL.	
Examiner	Art Unit	
le Ne Hines	1645	

	SEARCHED		
Class	Subclass	Date	Examiner
424	9.34, 130.1, 139.1, 150.1	6/15/2005	JAH
	178.1		
	184.1		
	185.1		
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	234.1		
	243.1		•
	244.1		
	278.1		
435	69.3		
436	86		
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930	10, 200		

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Search	ed ab	ve de	sses
and	l sub	class well	- As
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
STIC, West, derwent, commerical databases, biosis, medline, scisearch, biotechno, hcaplus, registry, wpids	6/15/2005	JAH
Sequence search, interference search, review of related patents and applications, inventor search		
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